

Sheet 01 of 02 Docket No. Serial No. Form PTO-1449 Modified NE-0002 10/681,874 List of Patents and Publications Applicant Cited by Applicant Borgstahl et al. (Use several sheets if necessary) Filing Date Group U.S. Department of Commerce October 7, 2003 Not Yet Assigned U. S. PATENT DOCUMENTS Examiner Document Date Name Class Subclass Initial No. BA 6,468,346 10-22-02 Arnowitz et al. 117 68 BB 6,385,289 5-7-02 Kikuchi 378 79 BC 6,498,829 12-24-02 Borgstahl et al. 378 73 FOREIGN PATENT DOCUMENTS Examiner Document No. Date Translation Country Initial YES NO wie y EXAMINER 2-11-05 DATE CONSIDERED

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U.S. Department of Commerce

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Applicant Borgstahl et 1.

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